



**DIODES, SWITCHING,
BASED ON TYPES 1N5807 THROUGH 1N5811
ESCC Detail Specification No. 5101/013**

**ISSUE 1
October 2002**



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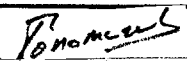
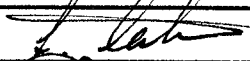


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DIODES, SWITCHING,
BASED ON TYPES 1N5807 THROUGH 1N5811
ESA/SCC Detail Specification No. 5101/013



**space components
coordination group**

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DOCUMENTATION CHANGE NOTICE

| Rev. Letter | Rev. Date | Reference | CHANGE Item | Approved DCR No. |
|-------------|-----------|---------------------------------------------------------------------------------------------------------------|------------------------------------------------------------|------------------|
| | | This Issue supersedes Issue 2 and incorporates all modifications defined in Issue 2 and the following DCR's:- | | |
| | | Cover Page | | None |
| | | DCN | | None |
| | | Table 1(b) | : No. 4, symbol corrected | 23476 |
| | | Para. 1.4 | : Text standardised | 23476 |
| | | Para. 2 | : Reference to ESA/SCC Basic Specification No. 23500 added | 21025 |
| | | Para. 4.2.2 | : PIND deviation deleted | 21043 |
| | | | : Reference to Para. 9.9.9 changed to 9.9.3 | None |
| | | Para. 4.2.3 | : Title corrected | 23476 |
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| | | Para. 4.7.3 | : Title and text standardised to include 'Power' | 23476 |
| | | Table 2 D.C. | : Format and sequence standardised | 23476 |
| | | Table 3 | : Format and sequence standardised | 23476 |
| | | Table 4 | : Numbering standardised | 23476 |
| | | Figure 5 | : Entry reference added | 23476 |
| | | Para. 4.8.1 | : Second sentence standardised | 23476 |
| | | Paras. 4.8.2 and 4.8.3 | : Paras. merged; following Paras. renumbered | 23476 |
| | | Para. 4.8.2 | : Second sentence added | 23476 |
| | | Para. 4.8.5 | : Last sentence amended | 23476 |
| | | Table 6 | : Format and numbering standardised | 23476 |
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| | | P2. DCN | | None |
| | | P8. Figure 3 | : Polarity marking reversed | 221466 |

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APPENDICES (Applicable to specific Manufacturers only)

None.

**1. GENERAL****1.1 SCOPE**

This specification details the ratings, physical and electrical characteristics, test and inspection data for Diodes, Switching, based on Type 1N5807 through 1N5811. It shall be read in conjunction with ESASCC Generic Specification No. 5000, the requirements of which are supplemented herein.

1.2 COMPONENT TYPE VARIANTS

Variants of the basic type diodes specified herein, which are also covered by this specification, are given in Table 1(a).

1.3 MAXIMUM RATINGS

The maximum ratings, which shall not be exceeded at any time during use or storage, applicable to the diodes specified herein, are as scheduled in Table 1(b).

1.4 PARAMETER DERATING INFORMATION

The parameter derating information applicable to the diodes specified herein, is shown in Figure 1.

1.5 PHYSICAL DIMENSIONS

The physical dimensions of the diodes specified herein, are shown in Figure 2.

1.6 FUNCTIONAL DIAGRAM

The functional diagram, showing lead identification, of the diodes specified herein, is shown in Figure 3.

1.7 HIGH TEMPERATURE TEST PRECAUTIONS

All tests to be performed at a temperature that exceeds +125°C shall be carried out in a 100% inert atmosphere.

**TABLE 1(a) - TYPE VARIANTS**

| (1) VARIANT | (2) BASED ON TYPE | (3) REVERSE VOLTAGE (V) | (4) LEAD MATERIAL AND/OR FINISH |
|----------------|-------------------------|----------------------------------|---------------------------------------|
| 01 | 1N5807 | 50 | Solid silver, uncoated |
| 02 | 1N5807 | 50 | A3 or A4 |
| 03 | 1N5808 | 75 | Solid silver, uncoated |
| 04 | 1N5808 | 75 | A3 or A4 |
| 05 | 1N5809 | 100 | Solid silver, uncoated |
| 06 | 1N5809 | 100 | A3 or A4 |
| 07 | 1N5810 | 125 | Solid silver, uncoated |
| 08 | 1N5810 | 125 | A3 or A4 |
| 09 | 1N5811 | 150 | Solid silver, uncoated |
| 10 | 1N5811 | 150 | A3 or A4 |

TABLE 1(b) - MAXIMUM RATINGS

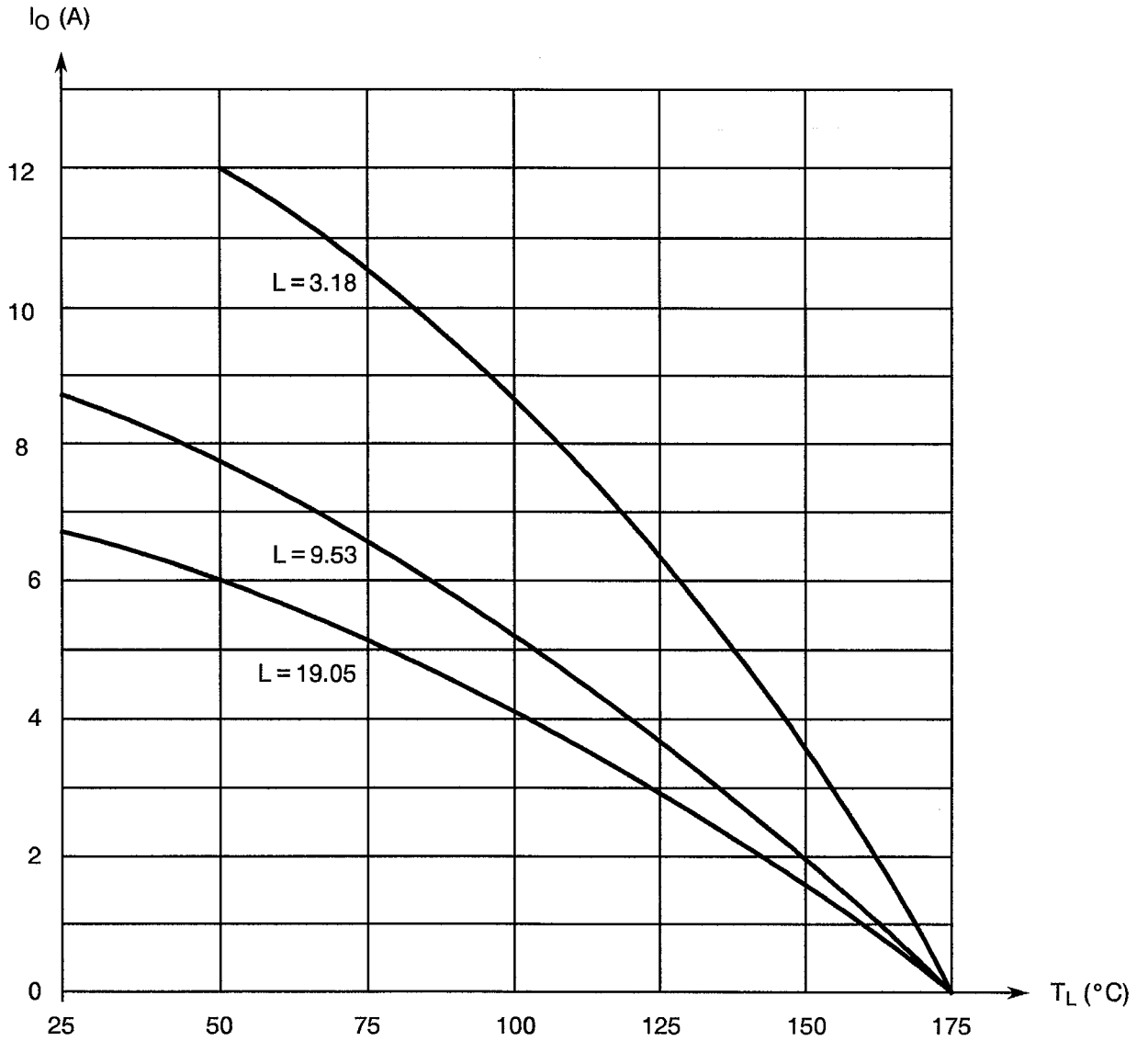
| No. | CHARACTERISTICS | SYMBOL | MAXIMUM RATING | UNIT | REMARKS |
|-----|----------------------------------|-----------|----------------|------|-----------|
| 1 | Forward Surge Current | I_{FSM} | 125 | A | Note 1 |
| 2 | Reverse Voltage | V_R | See Note 2 | V | |
| 3 | Average Output Rectified Current | I_O | 6.0 | A | Note 3 |
| 4 | Operating Temperature Range | T_{op} | -55 to +175 | °C | T_{amb} |
| 5 | Storage Temperature Range | T_{stg} | -65 to +200 | °C | |
| 6 | Soldering Temperature | T_{sol} | +260 | °C | Note 4 |

NOTES

1. Sinusoidal, with period = 8.3ms maximum.
2. See column (3) of Table 1(a).
3. For derating of I_O with T_C , see Figure 1.
4. Duration 10 seconds maximum at a distance of not less than 1.5mm from the can and the same lead shall not be resoldered until 3 minutes have elapsed.



FIGURE 1 - OUTPUT CURRENT DERATING WITH LEAD TEMPERATURE FOR DIFFERENT LEAD LENGTHS

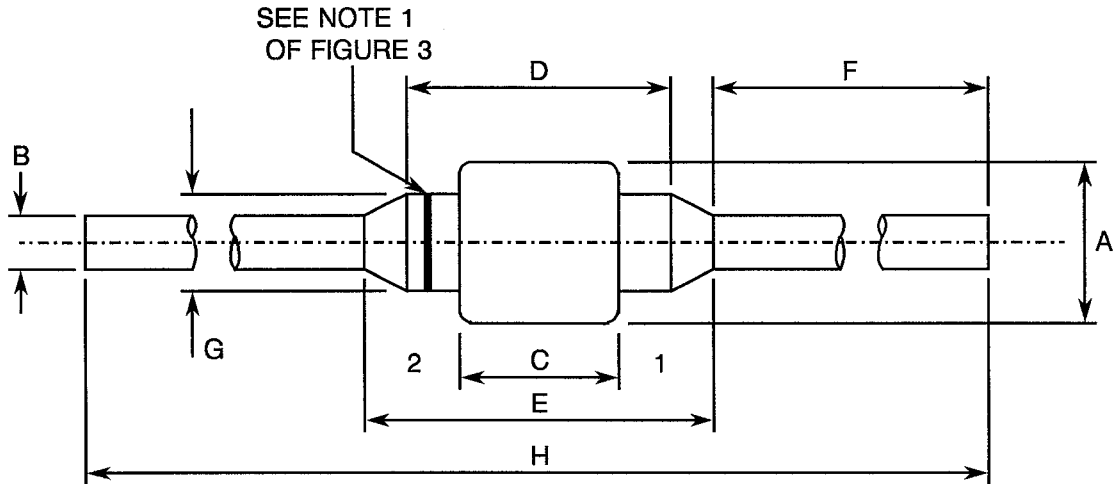


NOTES

1. L = Lead length from body in millimetres.

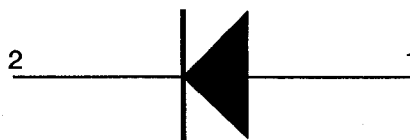


FIGURE 2 - PHYSICAL DIMENSIONS



| SYMBOL | MILLIMETRES | |
|--------|-------------|------|
| | MIN. | MAX. |
| A | - | 3.7 |
| B | 0.99 | 1.04 |
| C | - | 2.8 |
| D | - | 4.6 |
| E | - | 7.6 |
| F | 24.8 | - |
| G | - | 3.0 |
| H | 58.4 | - |

FIGURE 3 - FUNCTIONAL DIAGRAM



- 1. Anode.
- 2. Cathode.

NOTES

- 1. The cathode end shall be marked with a coloured ring.

**2. APPLICABLE DOCUMENTS**

The following documents form part of this specification and shall be read in conjunction with it:-

- (a) ESA/SCC Generic Specification No. 5000 for Discrete Semiconductors.
- (b) MIL-STD-750, Test Methods and Procedures for Semiconductor Devices.
- (c) MIL-S-13282, Silver and Silver Alloys.
- (d) MIL-STD-105, Sampling Procedures and Tables for Inspection by Attributes.
- (e) ESA/SCC Basic Specification No. 23500, Requirements for Lead Materials and Finishes for Space Application.

3. TERMS, DEFINITIONS, ABBREVIATIONS, SYMBOLS AND UNITS

For the purpose of this specification, the terms, definitions, abbreviations, symbols and units specified in ESA/SCC Basic Specification No. 21300 shall apply.

4. REQUIREMENTS**4.1 GENERAL**

The complete requirements for procurement of the diodes specified herein shall be as stated in this specification and ESA/SCC Generic Specification No. 5000 for Discrete Semiconductors. Deviations from the Generic Specification, applicable to this Detail Specification only, are listed in Para. 4.2.

Deviations from the applicable Generic Specification and this Detail Specification, formally agreed with specific Manufacturers on the basis that the alternative requirements are equivalent to the ESA/SCC requirements and do not affect the components' reliability, are listed in the appendices attached to this specification.

4.2 DEVIATIONS FROM GENERIC SPECIFICATION**4.2.1 Deviations from Special In-process Controls**

None.

4.2.2 Deviations from Final Production Tests (Chart II)

- (a) Para. 9.2.1, Bond Strength Test: Not applicable.
- (b) Para. 9.2.2, Die Shear Test: Not applicable.
- (c) The following test shall be added after Para. 9.8.2, "Seal Test, Fine and Gross Leak (optional)" and before Para. 9.9.3, "Electrical Measurements at Room Temperature":-

Surge Current in Accordance with MIL-STD-750, Test Method 4066. The following test conditions shall apply:-

| | | |
|------------------|---|------------------------|
| T_{amb} | = | $+25 \pm 3^{\circ}C$. |
| I_{FSM} | = | 125A. |
| Number of pulses | = | 5. |
| Pulse rate | = | 1 pulse/minute. |
| t_p | = | 8.3 ms. |
| Pulse form | = | sinusoidal. |

4.2.3 Deviations from Burn-in and Electrical Measurements (Chart III)

- (a) H.T.R.B. Test: Not applicable.

4.2.4 Deviations from Qualification Tests (Chart IV)

- (a) Para. 9.2.3, Bond Strength Test: Not applicable.
- (b) Para. 9.2.4, Die Shear Test: Not applicable.



4.2.5 Deviations from Lot Acceptance Tests (Chart V)

None.

4.3 MECHANICAL REQUIREMENTS

4.3.1 Dimension Check

The dimensions of the diodes specified herein shall be checked. They shall conform to those shown in Figure 2.

4.3.2 Weight

The maximum weight of the diodes specified herein shall be 0.25 grammes.

4.3.3 Terminal Strength

The requirements for terminal strength testing are specified in Section 9 of ESA/SCC Generic Specification No. 5000. The test conditions shall be as follows:-

Test Condition : 'A'.

Applied Force : 22.2 Newtons.

Duration : 15 seconds.

4.4 MATERIALS AND FINISHES

The materials and finishes shall be as specified herein. Where a definite material is not specified, a material which will enable the diodes specified herein to meet the performance requirements of this specification shall be used. Acceptance or approval of any constituent material does not guarantee acceptance of the finished product.

4.4.1 Case

The case shall be hermetically sealed and have a glass body.

4.4.2 Lead Material and Finish

The lead material shall be Type 'A' with Type '3' or Type '4' finish in accordance with the requirements of ESA/SCC Basic Specification No. 23500, or shall be solid silver, uncoated, in accordance with MIL-S-13282 (see Table 1(a) for Type Variants).

4.5 MARKING

4.5.1 General

The marking of all components delivered to this specification shall be in accordance with the requirements of ESA/SCC Basic Specification No. 21700. Each component shall be marked in respect of:-

(a) Lead Identification.

(b) The SCC Component Number.

(c) Traceability Information.

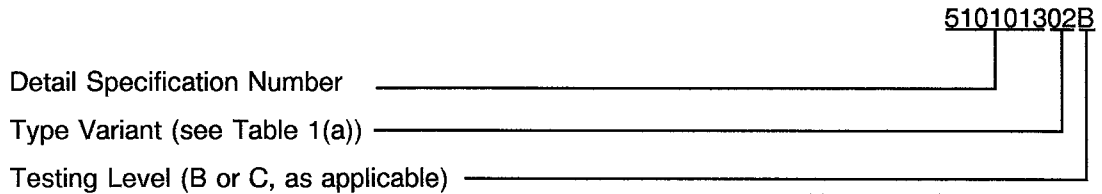
4.5.2 Lead Identification

Lead identification shall be as shown in Figures 2 and 3.



4.5.3 The SCC Component Number

Each component shall bear the SCC Component Number which shall be constituted and marked as follows:



4.5.4 Traceability Information

Each component shall be marked in respect of traceability information as defined in ESA/SCC Basic Specification No. 21700.

4.5.5 Marking of Small Components

When it is considered that the component is too small to accommodate the marking as specified above, as much as space permits shall be marked. The order of precedence shall be as follows:-

- (a) Lead identification.
- (b) The SCC Component number.
- (c) Traceability information.

The marking information in full shall accompany each component in its primary package.

4.6 ELECTRICAL MEASUREMENTS

4.6.1 Electrical Measurements at Room Temperature

The parameters to be measured at room temperature are scheduled in Table 2. The measurements shall be performed at $T_{amb} = +22 \pm 3 \text{ }^\circ\text{C}$.

4.6.2 Electrical Measurements at High and Low Temperatures

The parameters to be measured at high and low temperatures are scheduled in Table 3.

4.6.3 Circuits for Electrical Measurements

Circuits for use in performing electrical measurements listed in Tables 2 and 3 are shown, where applicable, in MIL-STD-750 and Figure 4.

4.7 BURN-IN TESTS

4.7.1 Parameter Drift Values

The parameter drift values applicable to burn-in are specified in Table 4 of this specification. Unless otherwise stated, measurements shall be performed at $T_{amb} = +22 \pm 3 \text{ }^\circ\text{C}$. The parameter drift values (Δ) applicable to the scheduled parameters shall not be exceeded. In addition to these drift value requirements for a given parameter, the appropriate limit value specified in Table 2 shall not be exceeded.

4.7.2 Conditions for Burn-in

The requirements for Burn-in are specified in Section 7 of ESA/SCC Generic Specification No. 5000. The conditions for Burn-in shall be as specified in Tables 5 of this specification.

4.7.3 Electrical Circuits for Burn-in

Not applicable.

**TABLE 2 - ELECTRICAL MEASUREMENTS AT ROOM TEMPERATURE - D.C. PARAMETERS**

| No. | CHARACTERISTICS | SYMBOL | MIL-STD-750 TEST METHOD | TEST CONDITIONS | LIMITS | | UNIT |
|-----|--------------------|--------|----------------------------|--------------------|--------|-------|---------|
| | | | | | MIN. | MAX. | |
| 1 | DC Forward Voltage | V_F | 4011 | $I_F = 4.0A$ | - | 0.875 | V |
| 2 | DC Reverse Current | I_R | 4016 | V_R : see Note 1 | - | 5.0 | μA |

NOTES

- See column (3) of Table 1(a).

TABLE 2 - ELECTRICAL MEASUREMENTS AT ROOM TEMPERATURE - A.C. PARAMETERS

| No. | CHARACTERISTICS | SYMBOL | MIL-STD-750 TEST METHOD | TEST CONDITIONS | LIMITS | | UNIT |
|-----|--------------------------|----------|----------------------------|-----------------------------------------------------------------|--------|------|------|
| | | | | | MIN. | MAX. | |
| 3 | Junction Capacitance | C_J | 4001 | $V_R = 10V$ $f = 1.0MHz$ | - | 50 | pF |
| 4 | Reverse Recovery Time | t_{rr} | 4031 | $I_F = 1.0A$ $I_R = 1.0A$ $I_{RR} = 0.1A$ See Figure 4 | - | 30 | ns |

TABLE 3 - ELECTRICAL MEASUREMENTS AT HIGH AND LOW TEMPERATURES

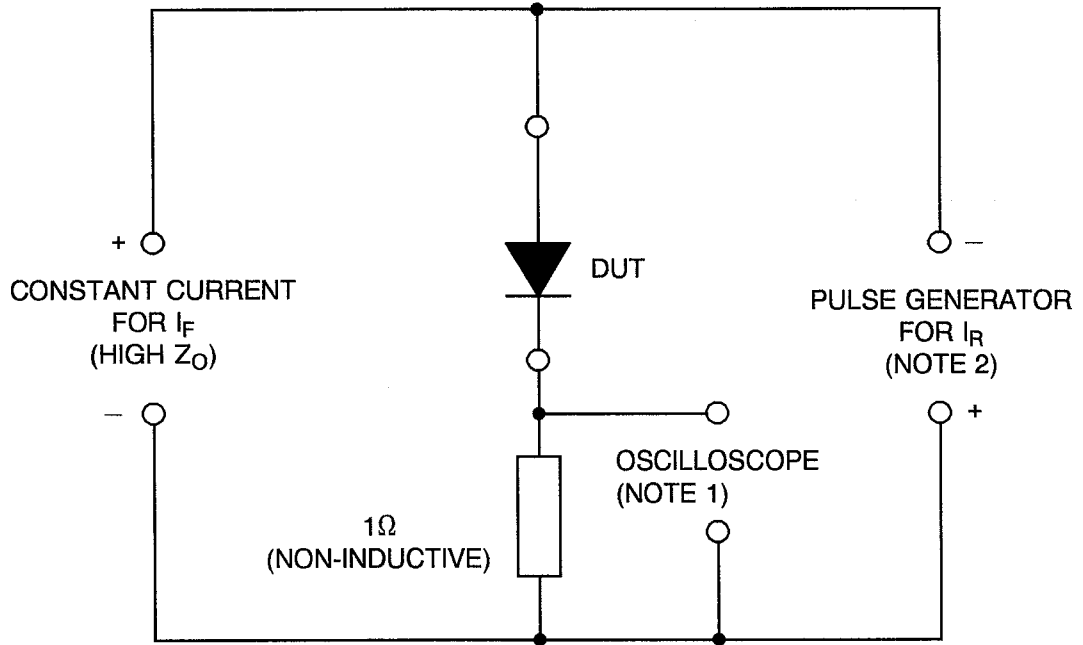
| No. | CHARACTERISTICS | SYMBOL | MIL-STD-750 TEST METHOD | TEST CONDITIONS | LIMITS | | UNIT |
|-----|--------------------------------|--------|----------------------------|------------------------------------------------------|--------|------|---------|
| | | | | | MIN. | MAX. | |
| 2 | DC Reverse Current (Note 2) | I_R | 4016 | $T_{amb} = 100(+0-5)^{\circ}C$ V_R : see Note 3 | - | 150 | μA |

NOTES

- Measurements at low temperature: Not applicable.
- Tests performed on a sample basis, Inspection Level II, Table IIA, AQL = 1.0 of MIL-STD-105. A minimum of 10% of parts shall be measured.
- See column (3) of Table 1(a).



FIGURE 4 - CIRCUITS FOR ELECTRICAL MEASUREMENTS - REVERSE RECOVERY TIME



NOTES

- 1. Oscilloscope: $t_r \leq 3.0\text{ns}$, $Z_{IN} = 50\Omega$.
- 2. Pulse generator: $t_r \leq 8.0\text{ns}$, $Z_S = 10\Omega$.

TABLE 4 - PARAMETER DRIFT VALUES

| No. | CHARACTERISTICS | SYMBOL | SPEC. AND/OR TEST METHOD | TEST CONDITIONS | CHANGE LIMITS | UNIT |
|-----|--------------------|--------|--------------------------|-----------------|---------------|---------------|
| 1 | DC Forward Voltage | V_F | As per Table 2 | As per Table 2 | ± 100 | mV |
| 2 | DC Reverse Current | I_R | As per Table 2 | As per Table 2 | ± 1.0 | μA |



TABLE 5 - CONDITIONS FOR BURN-IN AND OPERATING LIFE TEST

| No. | CHARACTERISTICS | SYMBOL | CONDITION | UNIT |
|-----|----------------------------------|--------|-------------------------------|--------------------|
| 1 | Case Temperature | T_C | $+ 100 \pm 0.5$ | $^{\circ}\text{C}$ |
| 2 | Working Voltage | V_B | $0.55 \times V_R$ (Note 1) | Vrms |
| 3 | Frequency | f | 50 or 60 | Hz |
| 4 | Average Output Rectified Current | I_O | 4.3 (Note 2) | A |

NOTES

1. See column (3) of Table 1(a).
2. Mounting shall be performed without bending or soldering the leads. Lead length from body to mounting shall be 3.14mm minimum.

FIGURE 5 - ELECTRICAL CIRCUIT FOR BURN-IN AND OPERATING LIFE TEST

Not applicable.



- 4.8 ENVIRONMENTAL AND ENDURANCE TESTS (CHARTS IV AND V OF ESA/SCC GENERIC SPECIFICATION NO. 5000)
- 4.8.1 Electrical Measurements on Completion of Environmental Tests
The parameters to be measured on completion of environmental tests are scheduled in Table 2. Unless otherwise stated, the measurements shall be performed at $T_{amb} = +22 \pm 3^{\circ}\text{C}$.
- 4.8.2 Electrical Measurements at Intermediate Points and on Completion of Endurance Tests
The parameters to be measured at intermediate points and on completion of endurance tests are scheduled in Table 6. Unless otherwise stated, the measurements shall be performed at $T_{amb} = +22 \pm 3^{\circ}\text{C}$.
- 4.8.3 Conditions for Operating Life Tests (Part of Endurance Testing)
The requirements for operating life testing are specified in Section 9 of ESA/SCC Generic Specification No. 5000. The conditions for operating life testing shall be the same as specified in Table 5 for the burn-in test.
- 4.8.4 Electrical Circuits for Operating Life Tests
Not applicable.
- 4.8.5 Conditions for High Temperature Storage Test (Part of Endurance Testing)
The requirements for the high temperature storage test are specified in ESA/SCC Generic Specification No. 5000. The temperature to be applied shall be the maximum storage temperature specified in Table 1(b) of this specification..

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**TABLE 6 - ELECTRICAL MEASUREMENTS AT INTERMEDIATE POINTS
AND ON COMPLETION OF ENDURANCE TESTS**

| No. | CHARACTERISTICS | SYMBOL | SPEC. AND/OR TEST METHOD | TEST CONDITIONS | LIMITS | | UNIT |
|-----|--------------------------|----------|-----------------------------|--------------------|--------|-------|---------|
| | | | | | MIN. | MAX. | |
| 1 | DC Forward Voltage | V_F | As per Table 2 | As per Table 2 | - | 0.875 | V |
| 2 | DC Reverse Current | I_R | As per Table 2 | As per Table 2 | - | 5.0 | μA |
| 3 | Reverse Recovery Time | t_{rr} | As per Table 2 | As per Table 2 | - | 30 | ns |